

Supporting Information

Morphology of OLED film stacks containing solution-processed phosphorescent dendrimers

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Table S1 – Room temperature models for films containing a *d*-CBP:IrG1 emissive layer

Film number	Layer material	Thickness [\AA]	SLD [10^{-6}\AA^{-2}]	Roughness [\AA]
1	<i>d</i> -CBP:IrG1	461 ± 1	4.12 ± 0.01	9 ± 1
2	PEDOT:PSS*	282 ± 1	1.92 ± 0.01	16 ± 1
	<i>d</i> -CBP:IrG1	464 ± 1	4.13 ± 0.01	9 ± 1
3	<i>d</i> -CBP:IrG1	430 ± 1	4.08 ± 0.01	12 ± 1
	TPBi	288 ± 1	2.72 ± 0.01	12 ± 1
4	PEDOT:PSS*	324 ± 1	1.90 ± 0.02	17 ± 1
	<i>d</i> -CBP:IrG1	452 ± 1	4.11 ± 0.01	9 ± 1
	TPBi	291 ± 1	2.75 ± 0.01	8 ± 1

* The thickness and SLD of the PEDOT:PSS layer was fixed during the temperature measurements as it did not appear to change.

Table S2 – Room temperature models for films containing a *d*-TCTA:IrG1 emissive layer

Film number	Layer material	Thickness [\AA]	SLD [10^{-6}\AA^{-2}]	Roughness [\AA]
5	<i>d</i> -TCTA:IrG1	442 ± 1	4.06 ± 0.01	10 ± 1
6	PEDOT:PSS*	324 ± 1	1.92 ± 0.01	17 ± 1
	<i>d</i> -TCTA:IrG1	460 ± 1	4.09 ± 0.01	9 ± 1
7	<i>d</i> -TCTA:IrG1	429 ± 1	4.09 ± 0.01	9 ± 1
	TPBi	287 ± 1	2.73 ± 0.01	7 ± 1
8	PEDOT:PSS*	322 ± 1	1.81 ± 0.02	14 ± 1
	<i>d</i> -TCTA:IrG1	446 ± 1	4.07 ± 0.01	9 ± 1
	TPBi	288 ± 1	2.75 ± 0.01	6 ± 1

* The thickness and SLD of the PEDOT:PSS layer was fixed during the temperature measurements as it did not appear to change.

Table S3 – Model parameters for Film **2** on thermal annealing

Temperature range (°C)	Layer (numbered from substrate upwards)	Thickness (Å)	SLD (10^{-6} Å^{-2})	Roughness (Å)
139 – 140	1 (PEDOT:PSS)	282	1.92	5
	2 (<i>d</i> -CBP:IrG1)	470	4.02	4
149 – 150	1	282	1.92	19
	2	469	4.03	4

Table S4 – Model parameters for Film 3 on thermal annealing

Temperature range (°C)	Layer (numbered from substrate upwards)	Thickness (Å)	SLD (10^{-6} Å $^{-2}$)	Roughness (Å)
90 – 91	1 (<i>d</i> -CBP:IrG1)	433	4.02	4
	2 (TPBi)	293	2.68	5
94 – 95	1	443	3.98	27
	2	288	2.71	4
100 – 101	1	494	3.84	5
	2	237	2.71	5
105 – 106	1	544	3.78	30
	2	197	2.70	10
110 – 111	1	563	3.67	33
	2	171	2.83	5
113 – 114	1	589	3.58	36
	2	144	3.02	4
117 – 118	1 (Completely mixed)	729	3.46	4
118 – 119	1	543	3.39	88
	2	182	3.65	4
159 – 160	1	612	3.40	63
	2	131	3.51	4

Table S5 – Model parameters for Film 4 on thermal annealing

Temperature range (°C)	Layer (numbered from substrate upwards)	Thickness (Å)	SLD (10^{-6} Å $^{-2}$)	Roughness (Å)
90 – 91	1 (PEDOT:PSS)	324	1.90	24
	2 (<i>d</i> -CBP:IrG1)	459	3.96	5
	3 (TPBi)	293	2.76	4
94 – 95	1	324	1.90	7
	2	469	3.92	30
	3	282	2.74	4
100 – 101	1	324	1.90	5
	2	522	3.77	4
	3	231	2.70	4
105 – 106	1	324	1.90	15
	2	559	3.73	5
	3	198	2.72	10
110 – 111	1	324	1.90	32
	2	590	3.60	41
	3	161	2.79	5
113 – 114	1	324	1.90	32
	2	598	3.58	29
	3	155	3.04	4
117 – 118	1	324	1.90	5
	2	753	3.46	4
118 – 119	1	324	1.90	15
	2	527	3.38	98
	3	225	3.62	4
159 – 160	1	324	1.90	8

	2	410	3.27	245
	3	343	3.56	4

Table S6 – Model parameters for Film **6** on thermal annealing

Temperature range (°C)	Layer (numbered from substrate upwards)	Thickness (Å)	SLD (10^{-6} Å $^{-2}$)	Roughness (Å)
139 – 140	1 (PEDOT:PSS)	324	1.92	17
	2 (<i>d</i> -TCTA:IrG1)	464	3.98	4
149 – 150	1	324	1.92	19
	2	459	3.93	4
159 – 160	1	324	1.92	25
	2	461	3.92	4

Table S7 – Model parameters for Film 7 on thermal annealing

Temperature range (°C)	Layer (numbered from substrate upwards)	Thickness (Å)	SLD (10^{-6} Å $^{-2}$)	Roughness (Å)
110 – 111	1 (PEDOT:PSS)	437	3.98	5
	2 (<i>d</i> -TCTA:IrG1)	293	2.70	6
115 – 116	1	437	3.99	13
	2	292	2.71	5
116 – 117	1	385	3.97	22
	2 (mixed interlayer)	70	3.56	18
	3	272	2.70	5
120 – 121	1	273	3.97	9
	2	235	3.58	20
	3	231	2.70	6
130 – 131	1	226	3.91	90
	2	346	3.41	14
	3	159	2.70	5
131 – 132	1	303	3.58	9
	2	301	3.49	15
	3	133	3.08	5
134 – 135	1 (completely mixed)	727	3.42	3
135 – 136	1	150	3.35	60
	2	418	3.39	95
	3	161	3.65	5
159 – 160	1	677	3.43	45
	2	59	3.65	6

Table S8 – Model parameters for Film **8** on thermal annealing

Temperature range (°C)	Layer (numbered from substrate upwards)	Thickness (Å)	SLD (10^{-6} Å $^{-2}$)	Roughness (Å)
110 – 111	1 (PEDOT:PSS)	322	1.81	16
	2 (<i>d</i> -TCTA:IrG1)	446	3.92	5
	3 (TPBi)	287	2.74	4
116 – 117	1	322	1.81	17
	2	445	3.91	20
	3	289	2.73	5
117 – 118	1	322	1.81	18
	2	430	3.90	17
	3 (mixed interlayer)	65	3.14	52
	4	240	2.70	6
120 – 121	1	322	1.81	17
	2	333	3.90	83
	3	187	3.45	17
	4	218	2.71	6
125 – 126	1	322	1.81	20
	2	102	4.06	113
	3	457	3.54	6
	4	181	2.70	10
129 – 130	1	322	1.81	23
	2	174	3.50	32
	3	417	3.53	6
	4	147	3.03	7
134 – 135	1	322	1.81	7
	2	122	3.11	63

	3	471	3.40	89
	4	145	3.42	6
135 – 136	1	322	1.81	5
	2	144	3.19	87
	3	478	3.36	118
	4	113	3.62	7
159 – 160	1	322	1.81	5
	2	229	3.21	57
	3	497	3.39	79
	4	10	3.65	10

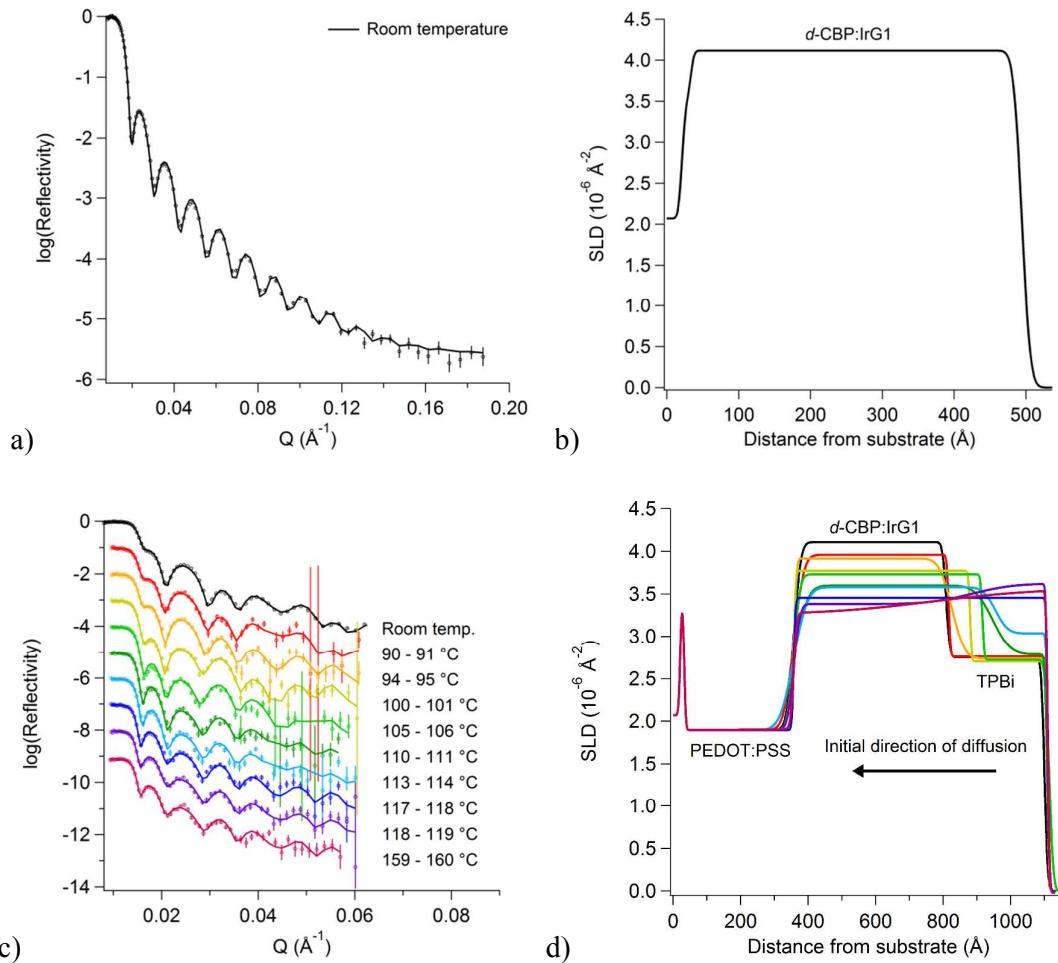


Figure S1 – a) Neutron reflectivity profiles and b) SLD *versus* distance from substrate plots for: a), b) Film 1 (*d*-CBP:IrG1); and c), d) Film 4 (PEDOT:PSS/*d*-CBP:IrG1/TPBi). NR profiles have been offset for clarity, with individual points indicating experimental data, and solid lines indicating model fits. In Figure S1 d) the arrow indicates the initial direction of material diffusion leading to the fully intermixed layer. Colours of thickness plots match the legend for the NR profiles.

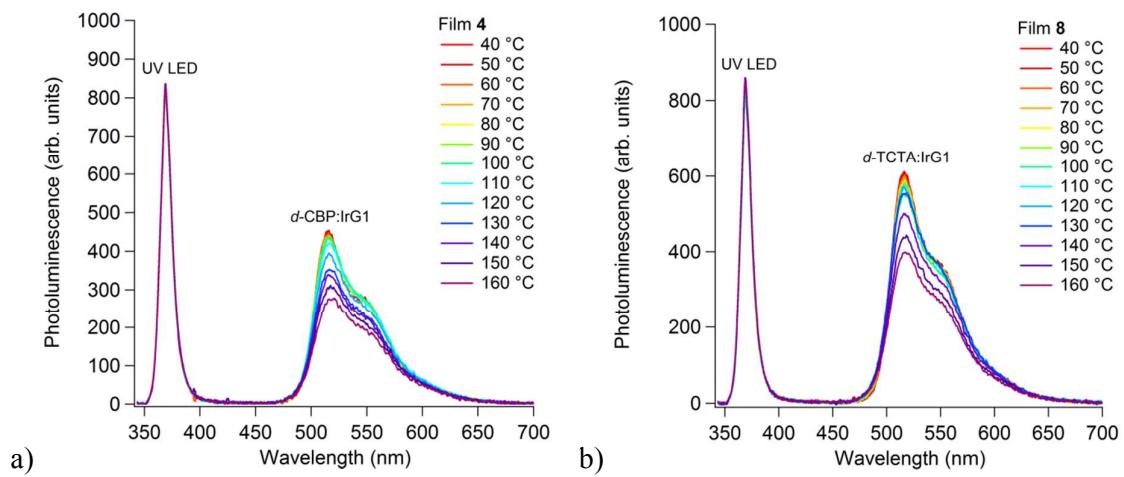


Figure S2 – *In situ* PL spectra for a) Film 4 (PEDOT:PSS/*d*-CBP:IrG1/TPBi); b) Film 8 (PEDOT:PSS/*d*-TCTA:IrG1/TPBi).

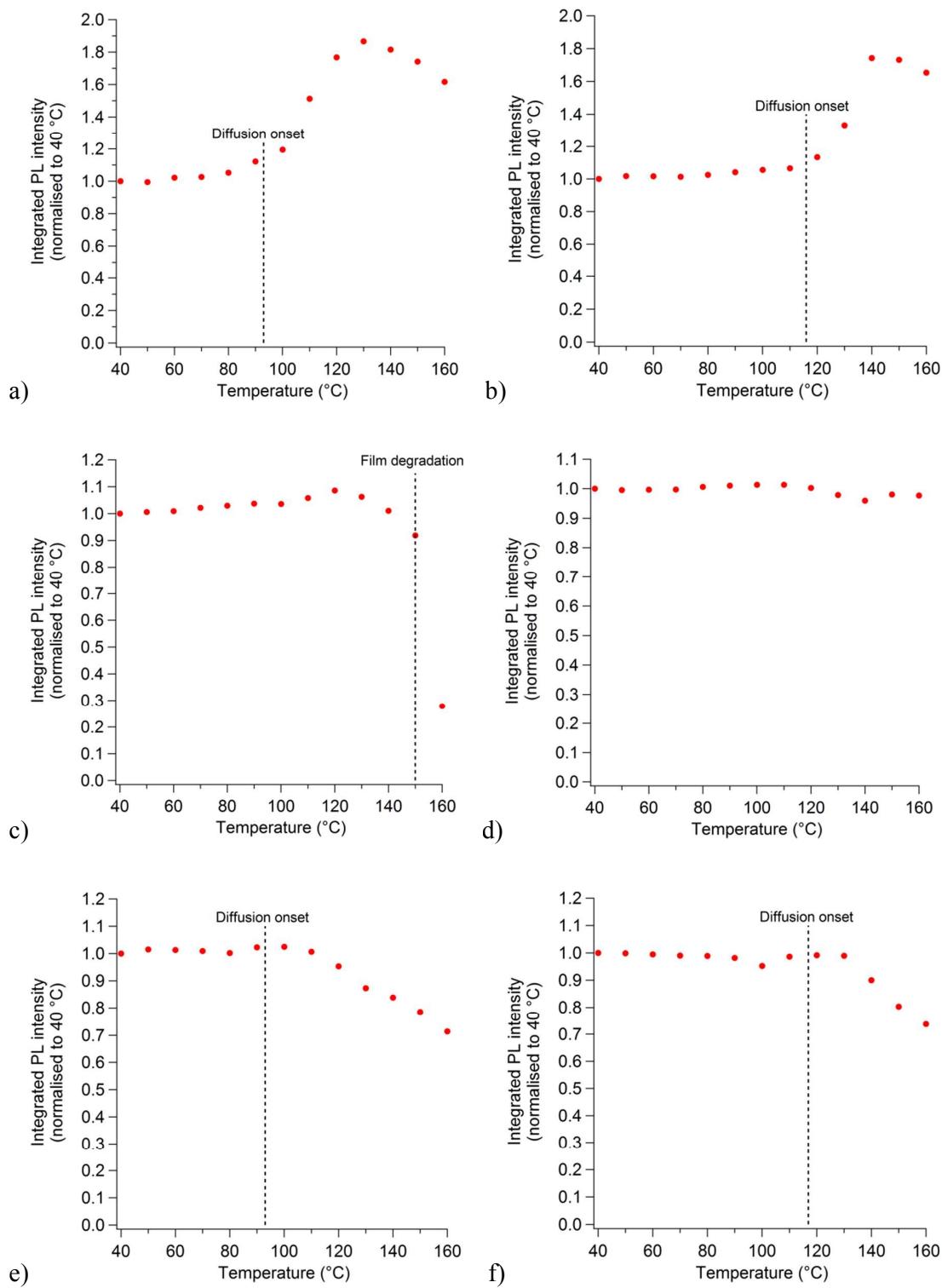


Figure S3 – Integrated PL intensity (normalised to the emission area at 40 °C) for a) Film 3 (*d*-CBP:IrG1/TPBi); b) Film 7 (*d*-TCTA:IrG1/TPBi) [between 475 and 650 nm]; c) Film 2 (PEDOT:PSS/ *d*-CBP:IrG1); d) Film 6 (PEDOT:PSS/*d*-TCTA:IrG1) [between 475 and 650 nm]; e) Film 4 (PEDOT:PSS/*d*-CBP:IrG1/TPBi); f) Film 8 (PEDOT:PSS/*d*-TCTA:IrG1/TPBi) [between 475 and 650 nm].

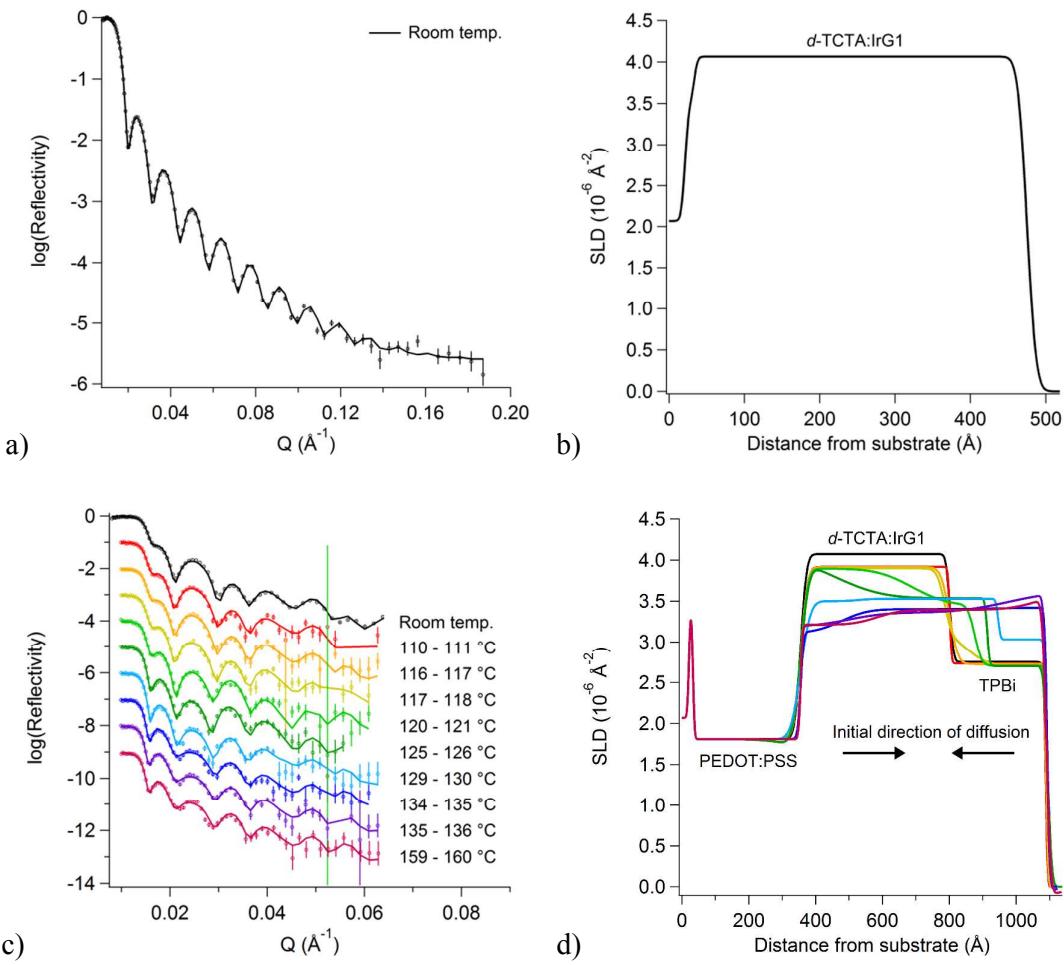


Figure S4 – Neutron reflectivity profiles and SLD *versus* distance from substrate plots for: a, b) Film 5 (*d*-TCTA:IrG1); and c, d) Film 8 (PEDOT:PSS/*d*-TCTA:IrG1/TPBi). NR profiles have been offset for clarity, with individual points indicating experimental data, and solid lines indicating model fits. In Figure S4 d) the arrows indicate the initial direction of material diffusion leading to the intermixed layer. Colours of thickness plots match the legend for the NR profiles.

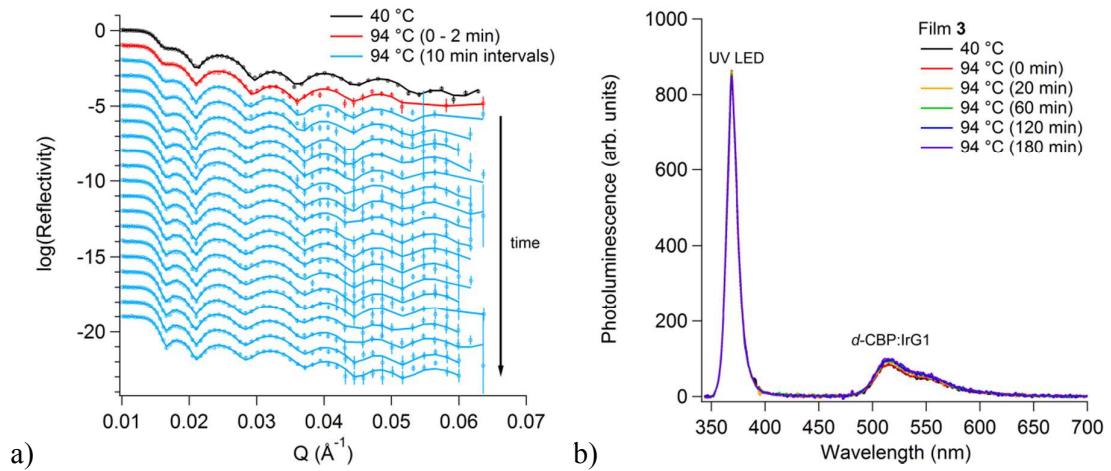


Figure S5 – a) Time resolved neutron reflectivity profiles, b) PL spectra for Film 3 (d -CBP:IrG1/TPBi) held at 94°C .

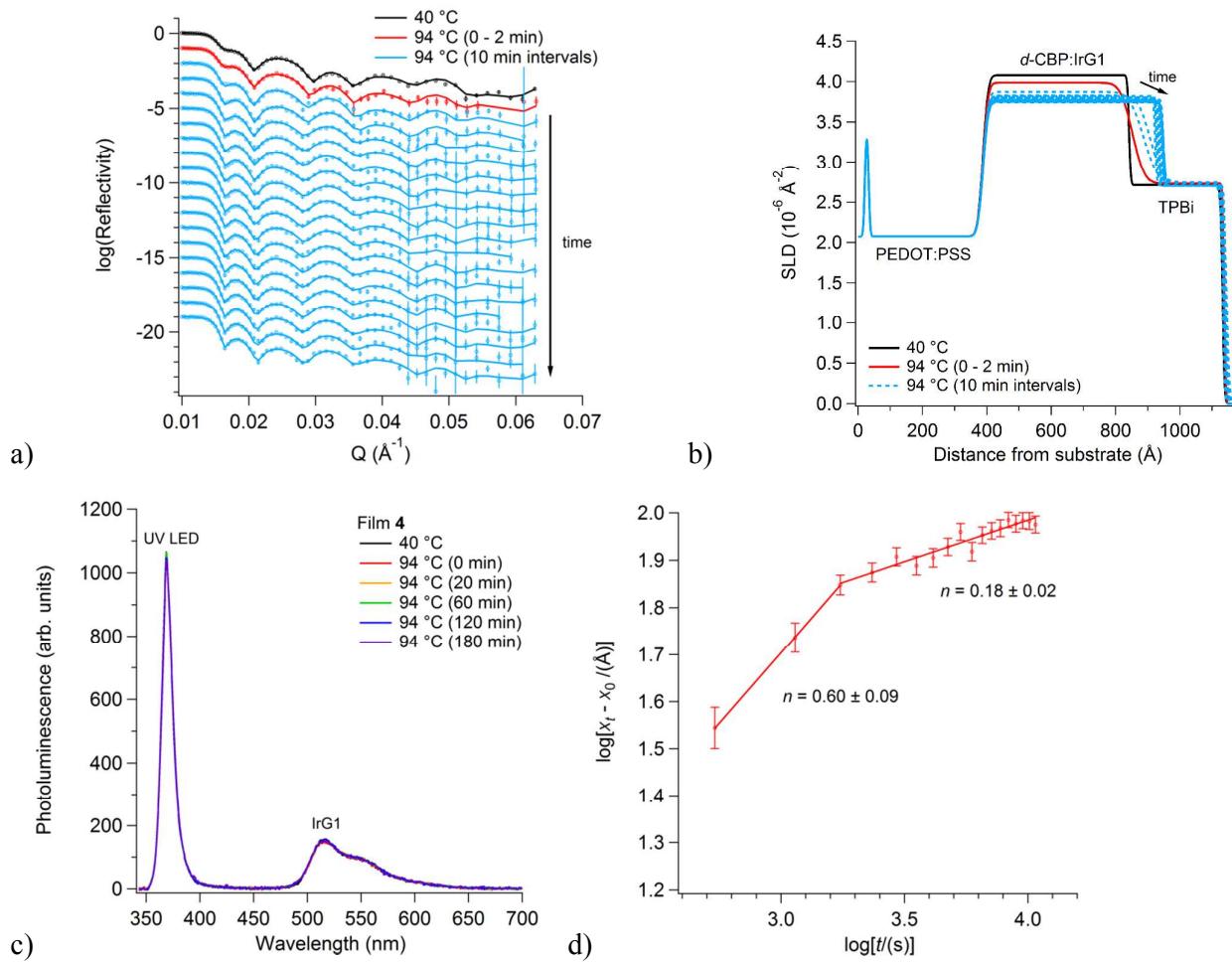


Figure S6 – a) Neutron reflectivity profiles, b) SLD *versus* distance from substrate plots, with the arrow representing the movement direction of the interface from which d) is determined, c) PL spectra, and d) plot relating the interface position to time (log-log plot) for Film 4 (PEDOT:PSS/ $d\text{-CBP:IrG1/TPBi}$).

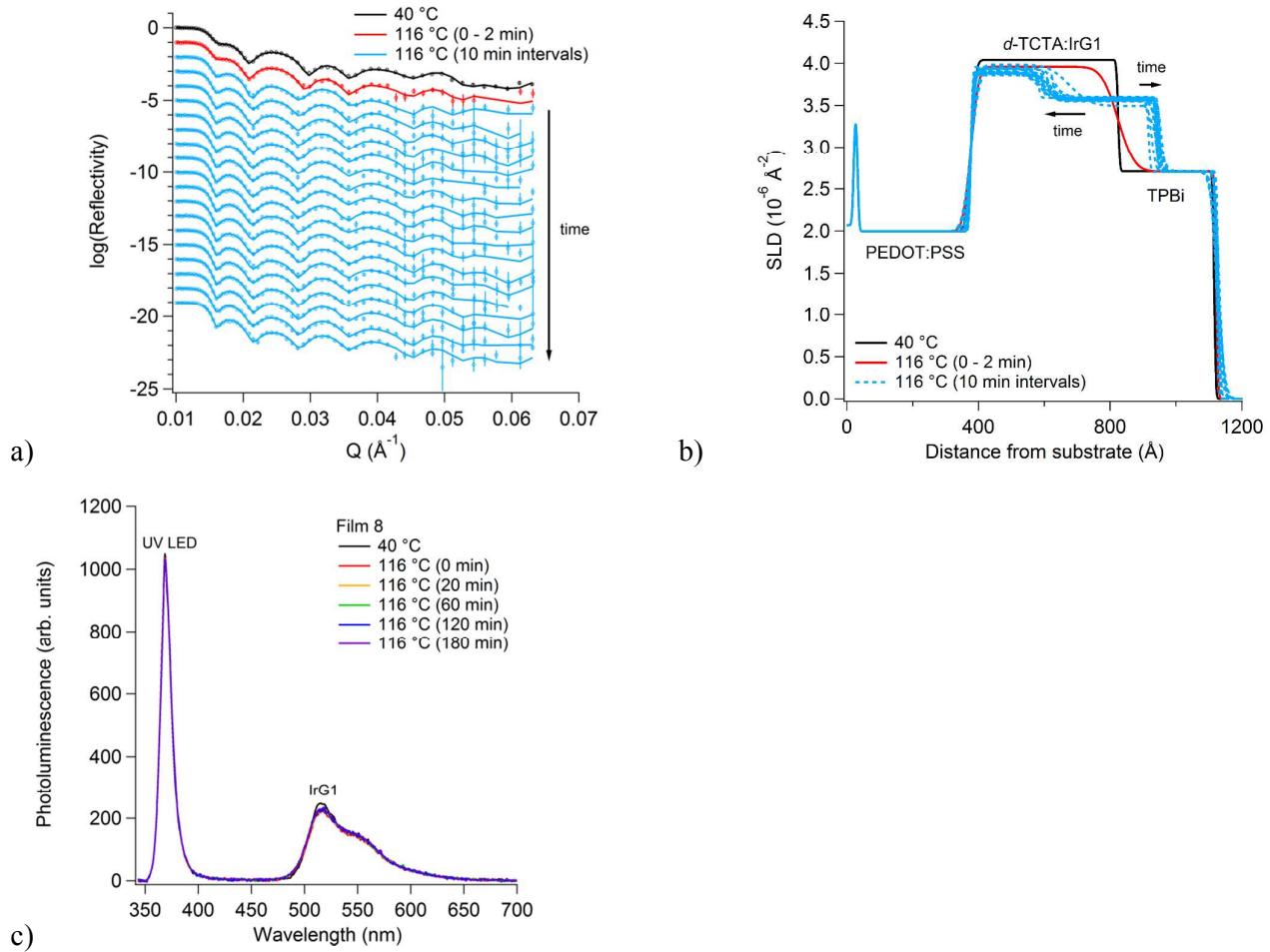


Figure S7 – a) Neutron reflectivity profiles, b) SLD *versus* distance from substrate plots (the arrows represent the movement direction of the interfaces), and c) PL spectra for Film 8 (PEDOT:PSS/*d*-TCTA:IrG1/TPBi).